

ABSTRACT OF THE DISCLOSURE:

A chip tester includes a heat-exchanger which regulates the temperature of an integrated circuit chip that is being tested by pressing against the chip. The heat-exchanger incorporates an electric heater and a heatsink that are joined together with a layer of attach material. The layer of attach material is limited to one that can be melted, at least partially, at a predetermined temperature, and re-solidified, multiple times. A spacer is in the heat-exchanger which stays solid at the predetermined temperature and which keeps the layer of attach material at a constant thickness.